

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10561696	YAKURA ET AL.
<b>Examiner</b>		<b>Art Unit</b>
shih-wen hsieh		2861

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
347	22-35	3-31-09	SWH

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
east text search	3-31-09	SWH

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

	/shih-wen hsieh/ Primary Examiner, Art Unit 2861
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